

Notice of References Cited	Application/Control No. 09/927,598	Applicant(s)/Patent Under Reexamination MILLER ET AL.	
	Examiner Sargon N. Nano	Art Unit 2157	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,708,213	03-2004	Bommaiah et al.	709/226
	B	US-6,526,022	02-2003	Chiu et al.	370/229
	C	US-6,405,256	06-2002	Lin et al.	709/231
	D	US-6,792,449	09-2004	Colville et al.	709/215
	E	US-6,772,193	08-2004	Igawa et al.	709/203
	F	US-6,757,796	06-2004	Hofmann, Markus	711/159
	G	US-6,657,955	12-2003	Bonneau et al.	370/229
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.